

**WHAT IS CLAIMED IS:**

1. A defect identifying apparatus, for inspecting and locating defects on an LCD substrate, said defect identifying apparatus comprising:

5       a microscope, including at least one objective lens and a base;  
      a defect marker fixed to said base, wherein said defect marker locates a defect.

2. The defect identifying apparatus of claim 1, wherein said defect  
10   marker further includes a marking tip positioned between said objective lens and a focal plane of said objective lens.

3. The defect identifying apparatus of claim 1, wherein said defect  
marker further includes an ink jet.

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4. A defect identifying apparatus, for inspecting and locating defects on an LCD substrate, said defect identifying apparatus comprising:  
      an inspection apparatus, including a base;  
      a defect marker fixed to said base, said defect marker including an ink jet,  
20   wherein said ink jet marks a defect.

5. The defect identifying apparatus of claim 4, wherein said inspection apparatus is a microscope.

6. The defect identifying apparatus of claim 5, wherein said microscope further includes an objective lens.

7. The defect identifying apparatus of claim 6, wherein said ink jet is  
5 positioned between said objective lens and a focal plane of said objective lens.